
**Anodizing of aluminium and its
alloys — Measurement of specular
reflectance and specular gloss of
anodic oxidation coatings at angles of
20°, 45°, 60° or 85°**

*Anodisation de l'aluminium et de ses alliages — Mesurage des
caractéristiques de réflectivité et de brillant spéculaires des couches
anodiques à angle fixe de 20°, 45°, 60° ou 85°*

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights. Details of any patent rights identified during the development of the document will be in the Introduction and/or on the ISO list of patent declarations received (see www.iso.org/patents).

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 79, *Light metals and their alloys*, Subcommittee SC 2, *Organic and anodic oxidation coatings on aluminium*, in collaboration with the European Committee for Standardization (CEN) Technical Committee CEN/TC 132, *Aluminium and aluminium alloys*, in accordance with the Agreement on technical cooperation between ISO and CEN (Vienna Agreement).

This fourth edition cancels and replaces the third edition (ISO 7668:2018), which has been technically revised. The main changes compared with the previous edition are as follows:

— [Tables 4](#) and [5](#) have been revised.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

Introduction

Specular reflectance and specular gloss are not unique physical properties of a surface. They vary with the angle of measurement, and with the aperture dimensions that define the incident and the reflected beams, such that measurements of these properties are not independent of the apparatus being used.

The specular reflectance of most surfaces increases with the angle of measurement and accounts for the use of reflectometers with various angles as, for example, for painted surfaces. The specular reflectance characteristics of anodized aluminium, however, do not always behave in the normal manner and, because of its property of double reflection, reflected light comes partly from the film surface and partly from the underlying metal. It is advisable to measure the specular reflectance characteristics at 20°, 45°, 60° and 85° to obtain a complete understanding of the specular reflectance properties of the anodized surface, and careful thought should be given to which method or methods are most relevant in any particular situation. The specular reflectance of bright-anodized aluminium with a mirror finish is best measured using 45° or 20° geometry.

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Anodizing of aluminium and its alloys — Measurement of specular reflectance and specular gloss of anodic oxidation coatings at angles of 20°, 45°, 60° or 85°

1 Scope

This document specifies methods for the measurement of specular reflectance and specular gloss of flat samples of anodized aluminium using geometries of 20° (Method A), 45° (Method B), 60° (Method C) and 85° (Method D) and of specular reflectance by an additional 45° method (Method E) employing a narrow acceptance angle.

The methods described are intended mainly for use with clear anodized surfaces. They can be used with colour-anodized aluminium, but only with similar colours.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 7583, *Anodizing of aluminium and its alloys — Terms and definitions*

ISO/CIE 11664-1, *Colorimetry — Part 1: CIE standard colorimetric observers*

ISO 11664-2, *Colorimetry — Part 2: CIE standard illuminants*

CIE Publication No. 15, *Colorimetry*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 7583 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- ISO Online browsing platform: available at <https://www.iso.org/obp>
- IEC Electropedia: available at <https://www.electropedia.org/>

3.1

specular reflectance

ratio of the luminous flux, reflected in the specular direction for a specified source and receptor angle, to the luminous flux of the incident light

Note 1 to entry: Usually expressed as a percentage.

— for Method E: $45^\circ \pm 0,1^\circ$.

There shall be no vignetting of rays that lie within the angles specified above.

The axis of the receptor shall, as far as possible, coincide with the mirror image of the axis of the incident beam; the receptor angle, ε_2 , which is the angle between the axis of the receptor and the perpendicular to the surface under test, shall be for all methods such that

$$|\varepsilon_1 - \varepsilon_2| \leq 0,1^\circ$$

With a flat piece of polished glass or other front-surface mirror in the test specimen position, an image of the source shall be formed at the centre of the receptor aperture. The width of the illustrated area of the test specimen shall be not less than 10 mm.

The angular dimensions of the receptor apertures shall be measured from the receptor lenses. The dimensions and tolerances of the sources and receptors shall be as indicated in [Tables 1](#) and [2](#). [Figures 1](#), [2](#) and [3](#) give generalized illustrations of these dimensions. [Table 1](#) gives both angles and corresponding dimensions calculated for lenses of a focal length of 50 mm for Methods A, B, C and D. [Table 2](#) gives the angles and aperture dimensions for Method E. The angles are mandatory and the aperture sizes have been calculated from the corresponding angle, δ , as $2f(\tan \delta/2)$, where f is the focal length of the receptor lens.

Table 1 — Angles and dimensions of source image and receptor apertures for Methods A, B, C and D

Method(s)	Instrument characteristics	In plane of measurement		Perpendicular to plane of measurement	
		Angle δ_1 degrees (°)	Dimension ^a mm	Angle δ_2 degrees (°)	Dimension ^a mm
A, B, C and D	Source image size	0,75($\delta_{1\alpha}$)	0,65	2,5($\delta_{2\alpha}$)	2,18 ^b
	Tolerance	$\pm 0,25$	$\pm 0,22$	$\pm 0,5$	$\pm 0,44$
A	20° Receptor aperture	1,80($\delta_{1\beta}$)	1,57	3,6($\delta_{2\beta}$)	3,14
	Tolerance	$\pm 0,05$	$\pm 0,04$	$\pm 0,1$	$\pm 0,09$
B	45° Receptor aperture	4,4($\delta_{1\beta}$)	3,84	11,7($\delta_{2\beta}$)	10,25
	Tolerance	$\pm 0,1$	$\pm 0,09$	$\pm 0,2$	$\pm 0,17$
C	60° Receptor aperture	4,4($\delta_{1\beta}$)	3,84	11,7($\delta_{2\beta}$)	10,25
	Tolerance	$\pm 0,1$	$\pm 0,09$	$\pm 0,2$	$\pm 0,17$
D	85° Receptor aperture	4,0($\delta_{1\beta}$)	3,49	6,0($\delta_{2\beta}$)	5,24
	Tolerance	$\pm 0,3$	$\pm 0,26$	$\pm 0,3$	$\pm 0,26$

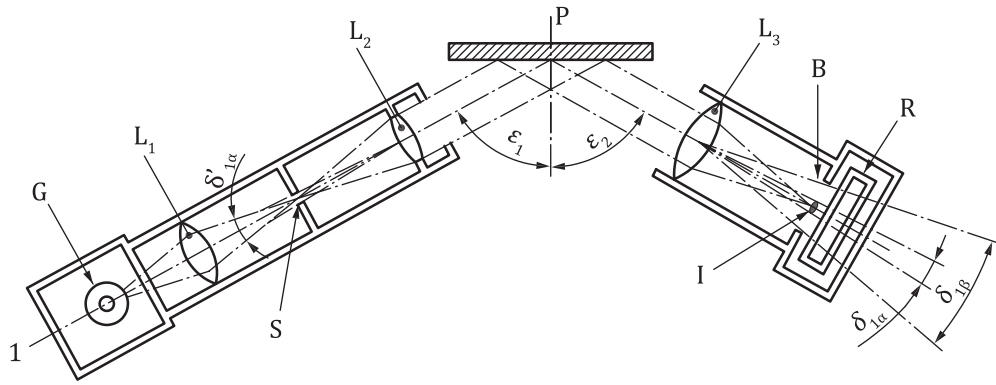
^a Calculated for a focal length of 50 mm. For any other focal length, f , these dimensions shall be multiplied by $f/50$.

^b $0,75^\circ \pm 0,25^\circ$, corresponding to dimensions of 0,65 mm \pm 0,22 mm, i.e. the same as those in the plane of measurement, is also recommended.

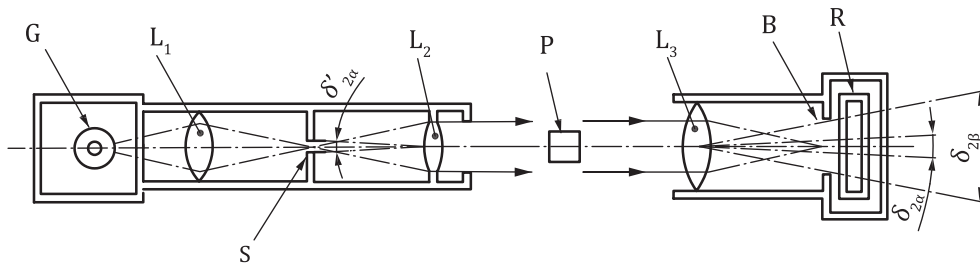
Table 2 — Angles and dimensions of circular source image and circular receptor aperture for 45° reflectometer of Method E

Instrument characteristics	Angle δ degrees (°)	Dimension ^a mm
Source image size	3,44	1,5
Tolerance	$\pm 0,23$	$\pm 0,1$
45° Receptor aperture	3,44	1,5
Tolerance	$\pm 0,23$	$\pm 0,1$

^a Calculated for focal length of 25,4 mm. For any other focal length, f , the aperture diameter is equal to $2f(\tan \delta/2)$.



a) In plane of measurement



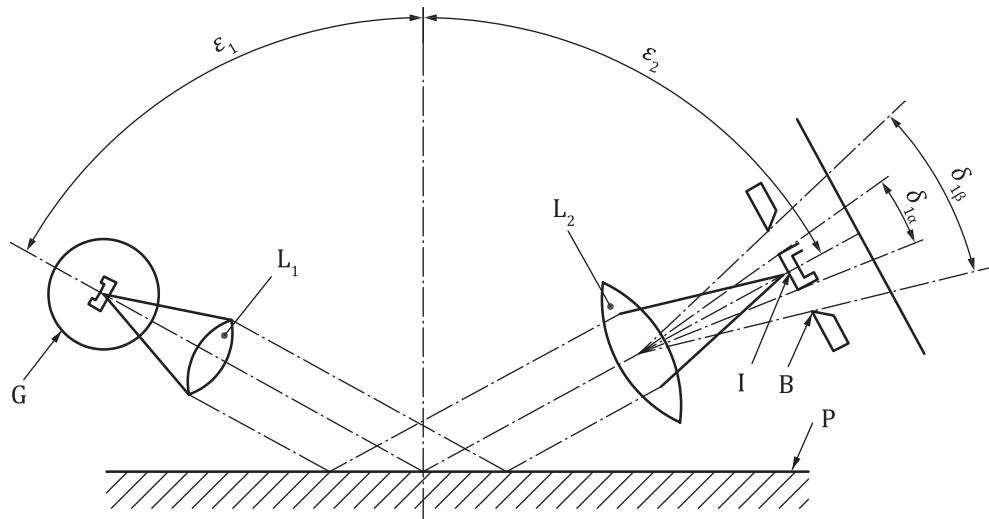
b) Perpendicular to plane of measurement

Key

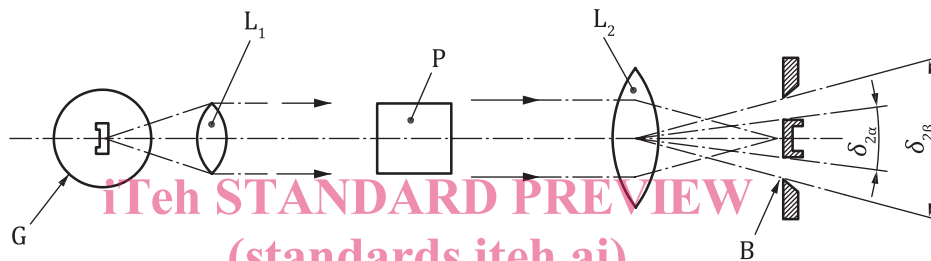
- | | | | |
|-------|-----------------------------------|--|--|
| 1 | axis | $\delta_{1\alpha}$ | source image angles (in plane of measurement) |
| G | filament lamp | $\delta_{1\beta}$ | receptor aperture angles (in plane of measurement) |
| L_1 | condenser lens | $\delta_{2\alpha}$ | source image angles (perpendicular to plane of measurement) |
| L_2 | collimator lens | $\delta_{2\beta}$ | receptor aperture angles (perpendicular to plane of measurement) |
| L_3 | receptor lens | $\delta'_{1\alpha} = \delta_{1\alpha}$ and $\delta'_{2\alpha} = \delta_{2\alpha}$ if the focal lengths of L_2 and L_3 are the same | |
| S | effective light source (pin note) | ϵ_1 | incident angle |
| P | test surface | ϵ_2 | receptor angle |
| B | receptor field aperture | | |
| I | source image | | |
| R | photoelectric cell | | |

NOTE Angles and dimensions are given in [Table 1](#).

Figure 1 — Schematic arrangement of apparatus showing apertures and source image formation for a collimated-beam-type instrument for Method A (20°), Method B (45°), Method C (60°) and Method D (85°)



a) In plane of measurement



b) Perpendicular to plane of measurement

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Key

- | | | | |
|-----------------|-------------------------|---|--------------------------|
| G | filament lamp | $\delta_{1\alpha}$ and $\delta_{2\alpha}$ | source image angles |
| L_1 and L_2 | lenses | $\delta_{1\beta}$ and $\delta_{2\beta}$ | receptor aperture angles |
| P | test surface | ϵ_1 | incident angle |
| B | receptor field aperture | ϵ_2 | receptor angle |
| I | image filament | | |

NOTE Angles and dimensions are given in [Table 1](#).

Figure 2 — Schematic arrangement of apparatus showing apertures and source image formation for a non-collimated-beam type instrument for Method A (20°), Method B (45°), Method C (60°) and Method D (85°)